



## Analysis of Low RRR SRF Cavities

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In partnership with:

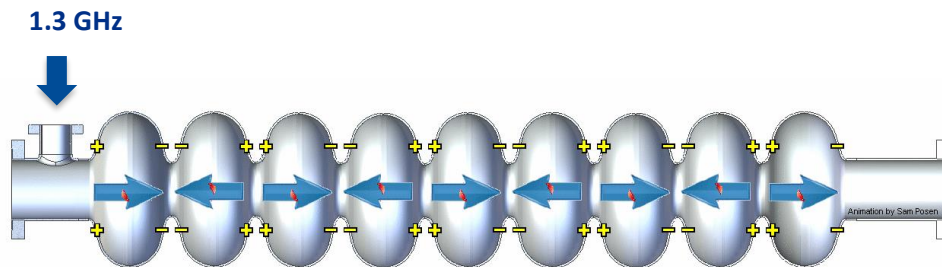


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# Introduction to Superconducting Radio Frequency (SRF) Cavities

- SRF cavities are resonant structures made from high purity niobium that generate the accelerating electric field along the beamline inside particle accelerators
- Purity measured by residual resistance ratio (RRR)
- Cavity performance determined by first ~100 nm of material
- Goals of SRF studies is to design surface profile to increase:
  - quality factor (efficiency)
  - accelerating gradient

$$Q_0 = \frac{G}{R_s} \sim \text{Number of oscillations to dissipate stored energy}$$



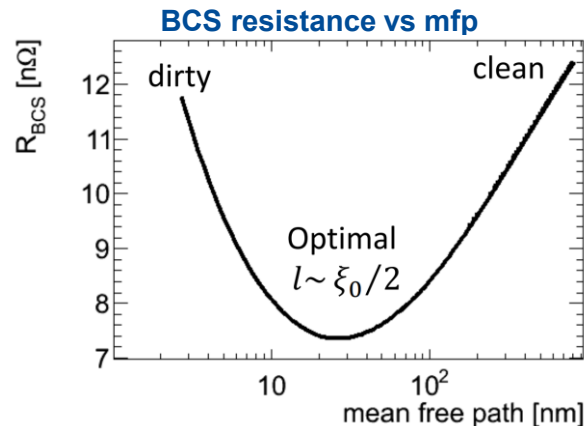
# Motivation for Low RRR Investigation

$$R_s(T) = R_{res}(< 1.5 K) + R_{BCS}(T)$$

↑  
Temperature  
Independent

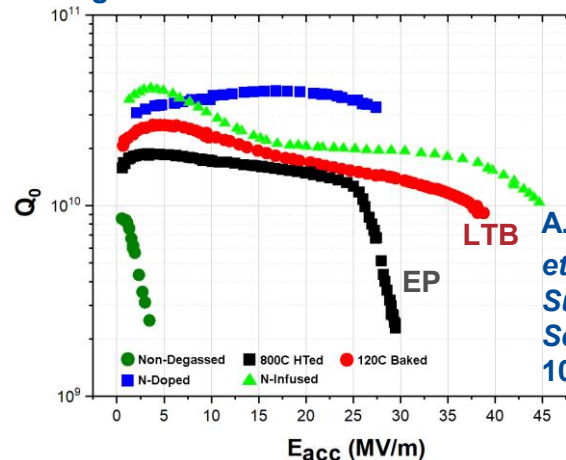
↑  
Temperature  
Dependent

- Many SRF studies follow a “clean bulk dirty surface” technique to optimize the BCS resistance by adding extrinsic impurities
  - Low temperature bake diffuses oxygen into surface
- What role do intrinsic impurities serve?
  - Lower the mfp so may experience low BCS resistance behavior
  - Might perform similar functions as extrinsic impurities which have been shown to improve performance



A. Miyazaki  
SRF2021  
Tutorial

Q vs gradient for different surface treatments



A. Grassellino  
et al 2013  
*Supercond.*  
*Sci. Technol.* 26  
102001

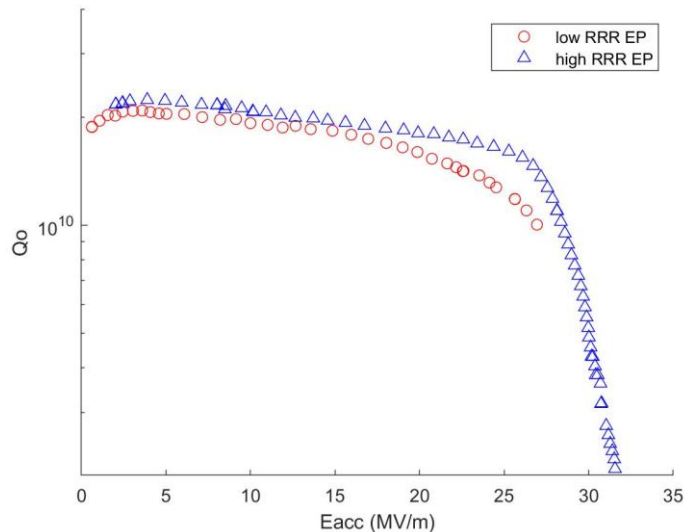
# Low RRR Analysis Components

- Baseline testing on 1.3 GHz TESLA-shaped single-cell low RRR (= 61) cavity in electropolished (EP) condition
  - Quality factor vs accelerating gradient at 2 K and low T (< 1.5 K)
  - Residual resistance vs gradient
  - BCS resistance vs gradient
  - Frequency vs temperature
- Repeat testing after surface treatment
  - Low temperature bake (120 °C x 48 hours)



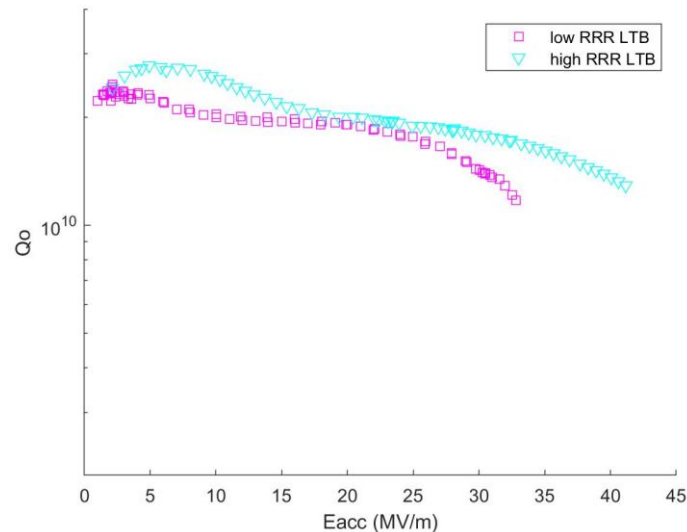
Cavity testing facility at Fermilab

# Quality Factor vs Accelerating Gradient at 2 K



## Electropolished

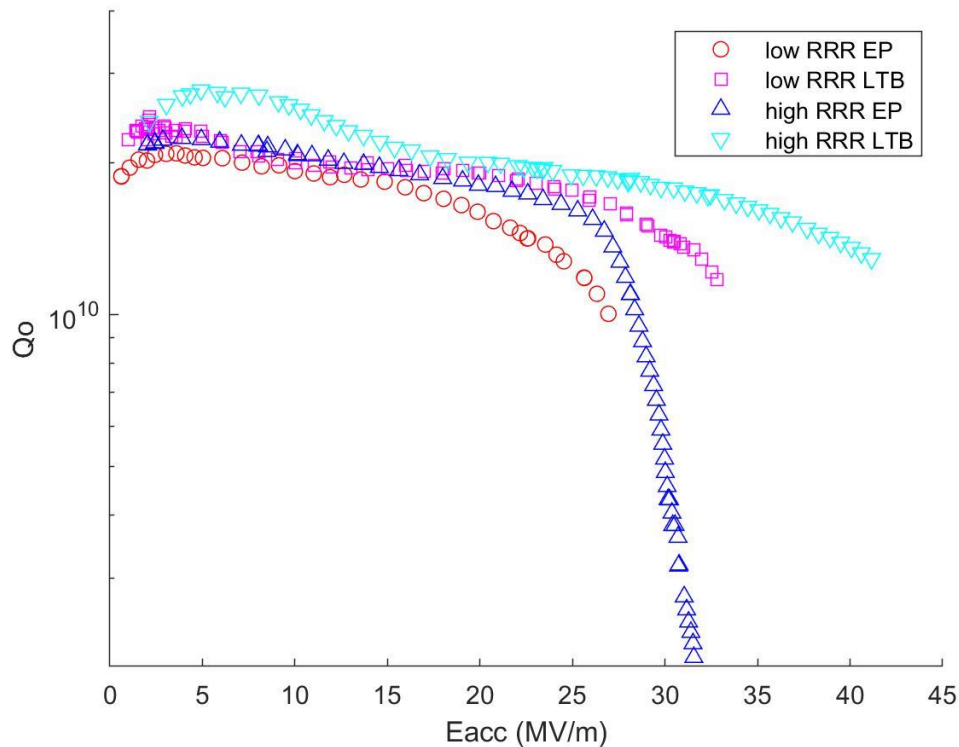
- Low RRR has slightly lower  $Q_0$  at all gradients and does not reach as high gradient
- $Q_0$  slope begins sooner but less sharp



## Low Temperature Bake

- Low RRR does not experience “bump” of anti  $Q_0$  slope at low gradient
- Performance is extended from EP but not as far as high RRR

# Quality Factor vs Accelerating Gradient at 2 K

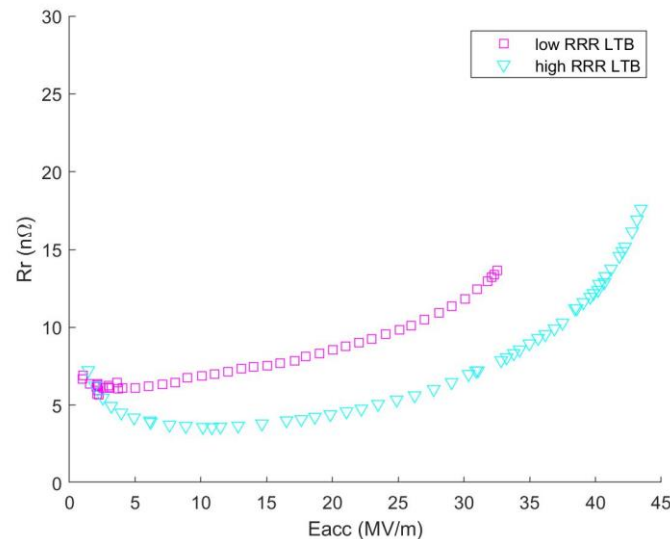
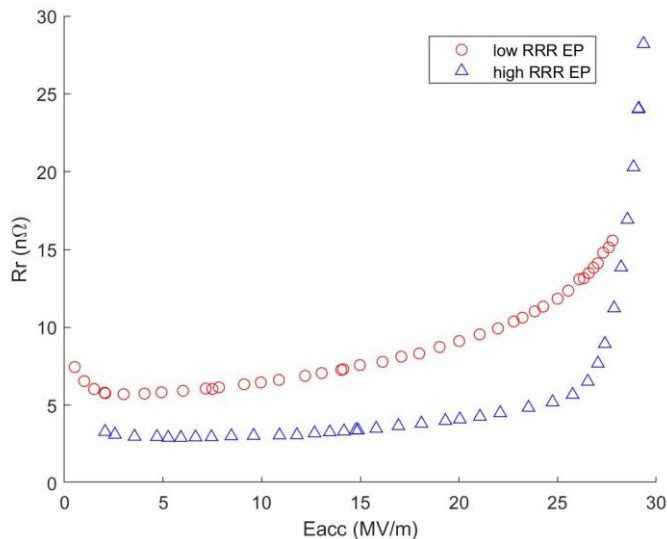


LTB improves performance of low RRR cavity but in a different way than we see in high RRR cavities

- Performance of all cavities is similar at medium gradients
- LTB delays  $Q_0$  slope in low RRR but less extreme difference than high RRR
- Low RRR does not experience anti  $Q_0$  slope after LTB

# Residual Resistance vs Accelerating Gradient

$$R_{res} = \frac{G=270 \Omega}{Q_0(low T)}$$



## Electropolished

- Low RRR almost always a few  $n\Omega$  higher than high RRR

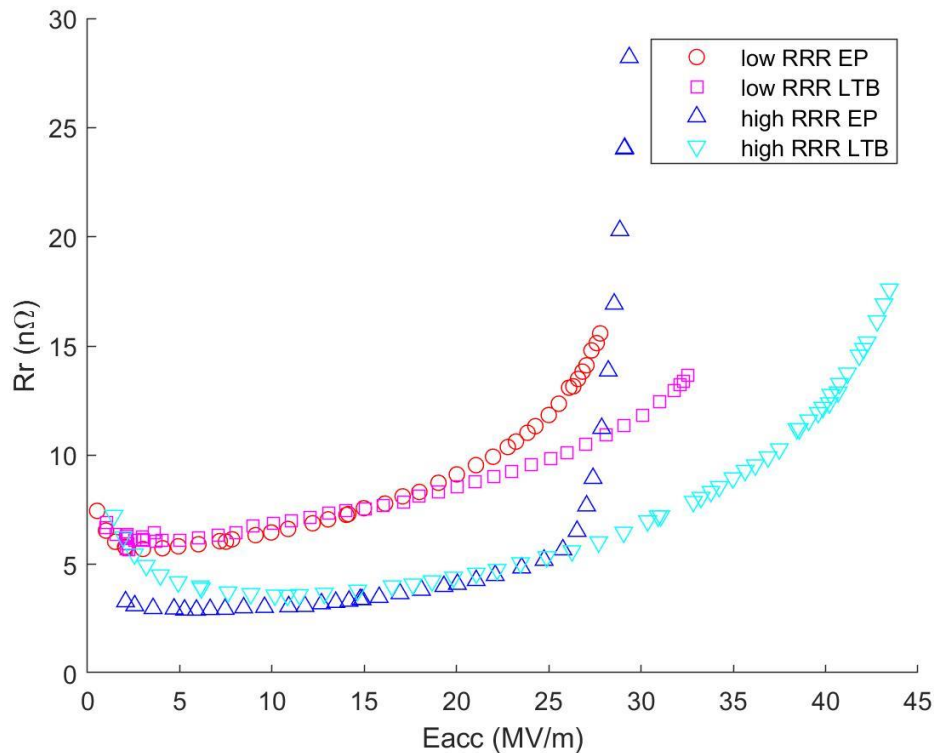
## Low Temperature Bake

- Similar at low field but then low RRR steadily increases
- Parallel at high field



# Residual Resistance vs Accelerating Gradient

$$R_{res} = \frac{G=270 \Omega}{Q_0(low T)}$$



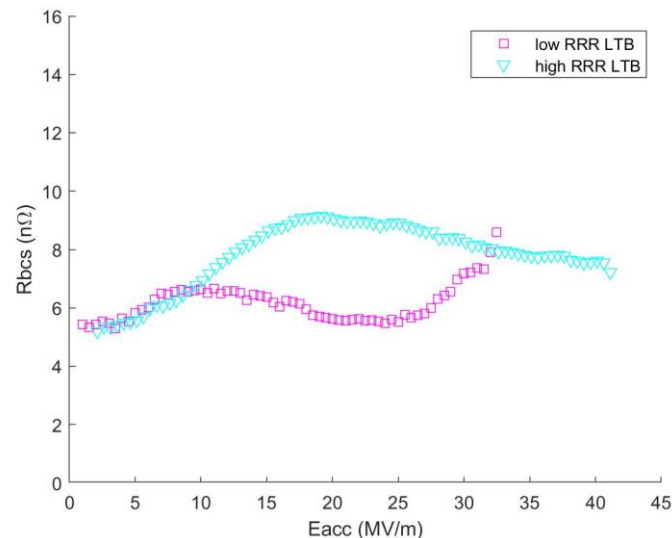
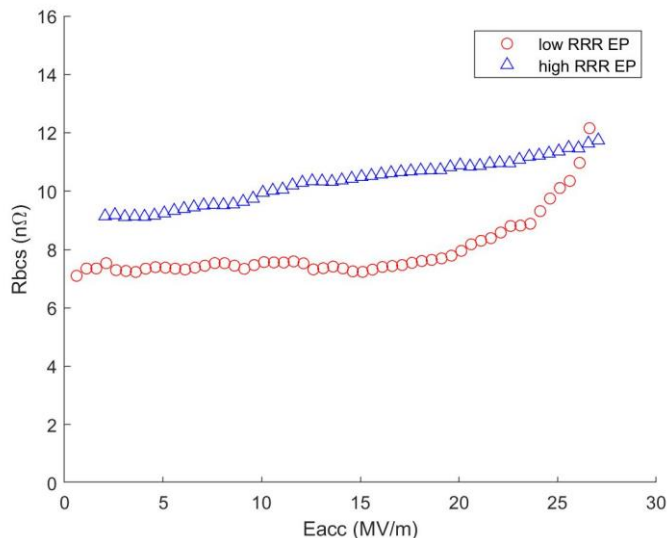
Low RRR and high RRR have similar residual resistance response to LTB

- Low RRR EP and LTB nearly equal until  $\sim 20$  MV/m
- High RRR EP and LTB same at medium field
- Low RRR almost always larger residual resistance than high RRR



# BCS Resistance vs Accelerating Gradient

$$R_{BCS}(2\text{ K}) = R_s(2\text{ K}) - R_{res}$$



## Electropolished

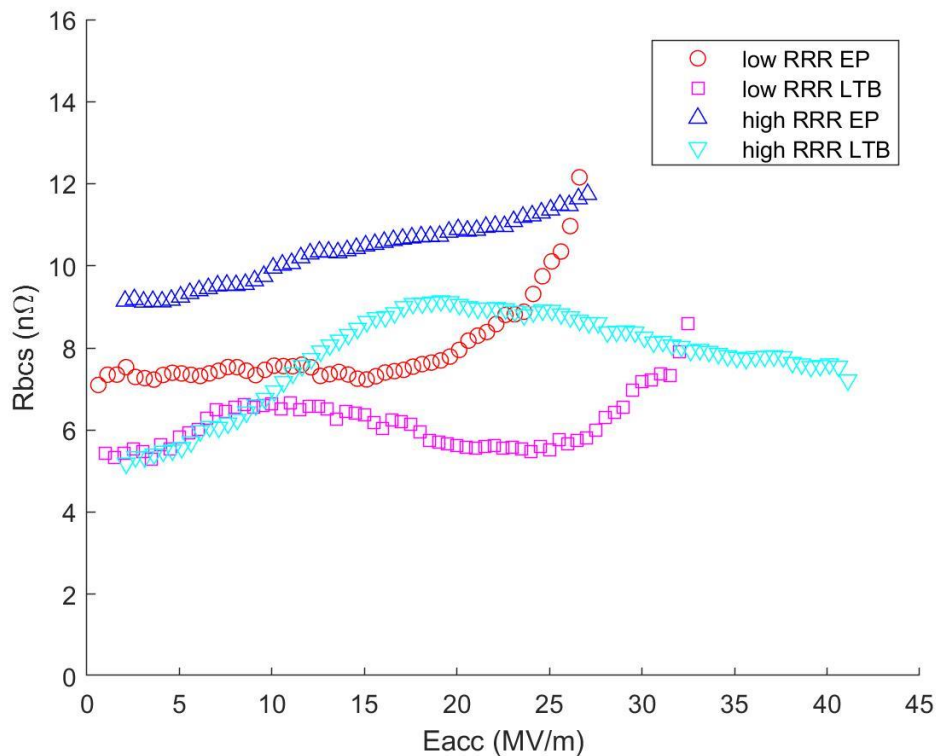
- Low RRR is significantly lower except at high field

## Low Temperature Bake

- High and low RRR equal until ~10 MV/m
- Low RRR has lower BCS resistance at mid field

# BCS Resistance vs Accelerating Gradient

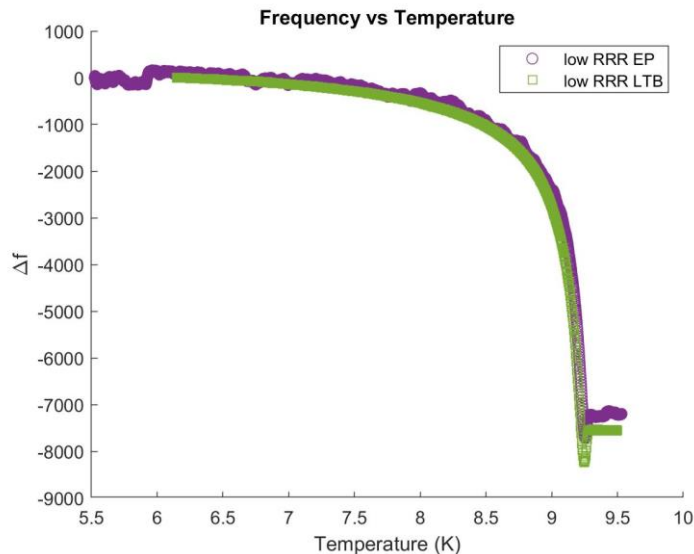
$$R_{BCS}(2\text{ K}) = R_s(2\text{ K}) - R_{res}$$



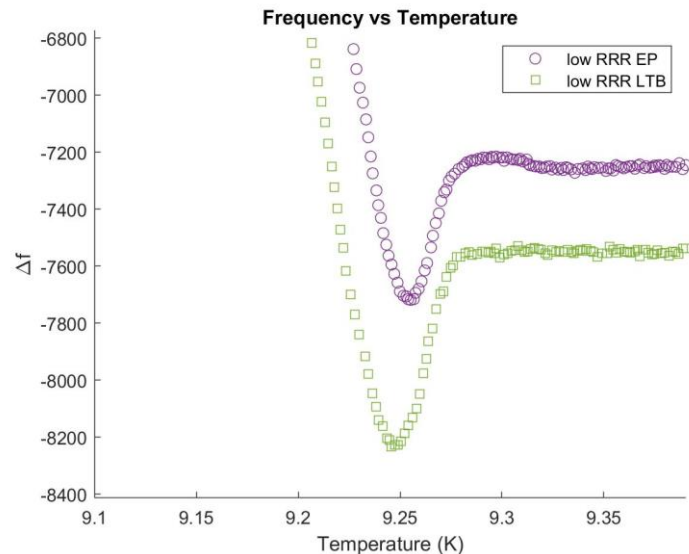
Low RRR exhibits low BCS behavior

- EP  $\rightarrow$  LTB causes downright shift in BCS resistance
- Low RRR BCS is lowest at mid field
- Any benefit of dirty surface is lost at high field

# Frequency vs Temperature

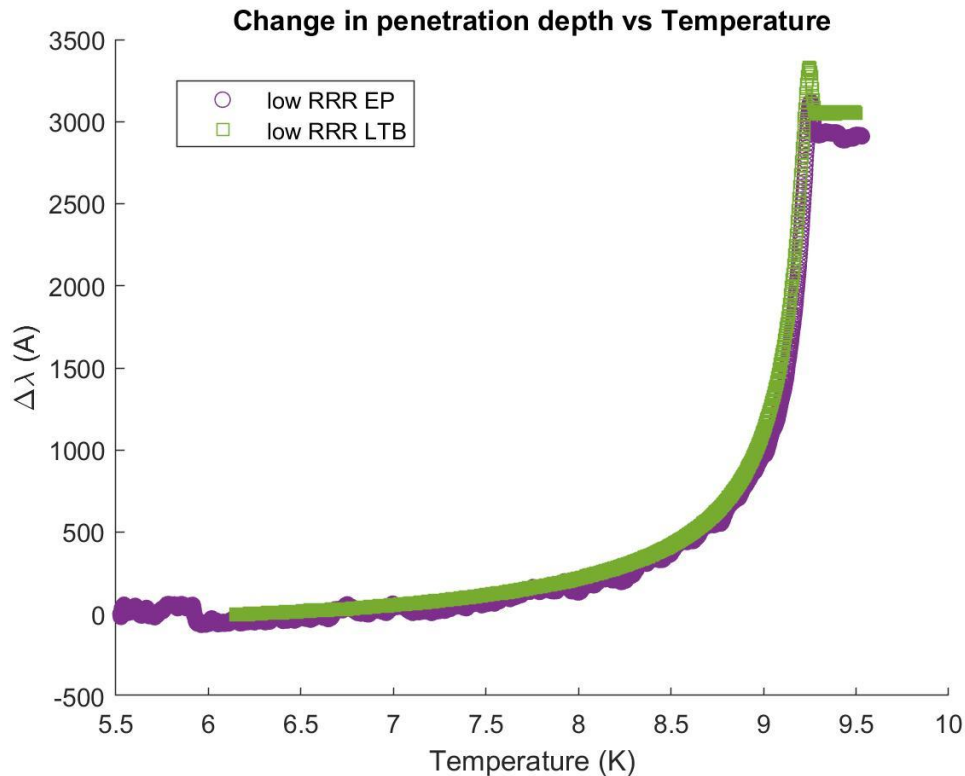


- EP and LTB experience ~7.5 kHz change in resonant frequency through  $T_c$



- Dip in EP and LTB  $\rightarrow$  doped behavior
- Experimental  $T_c$  for both ~9.28 K

# Change in Penetration Depth vs Temperature

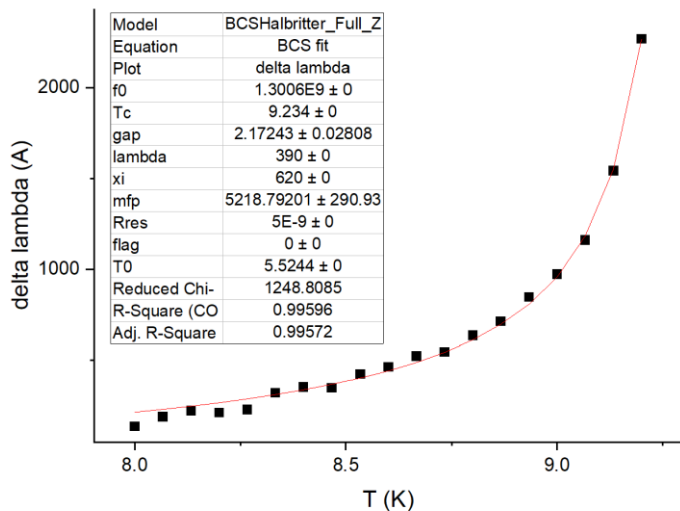


$$\Delta\lambda(T) = - \frac{G\Delta f(T)}{\mu_0 f^2(T_0)}$$

Need to convert to penetration depth to use fitting program to find mfp and gap

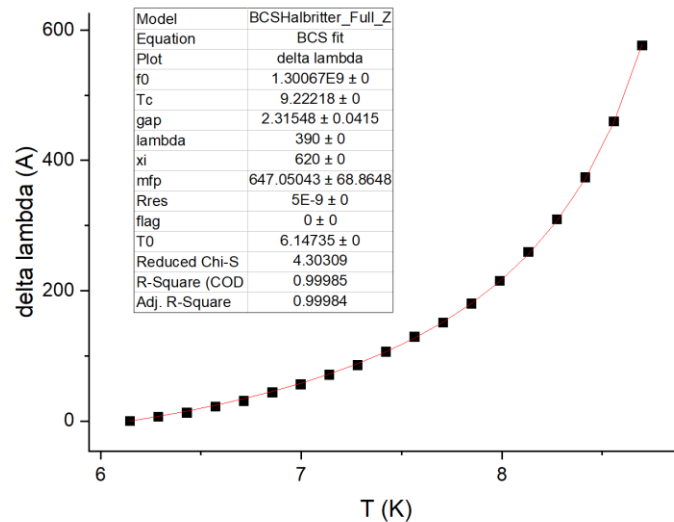
- $G = 270 \, \Omega$  (geometry factor)
- $\Delta f(T)$  = change in frequency vs temperature
- $\mu_0$  = magnetic permeability
- $f(T_0)$  = constant resonant frequency at low temperature

# Nonlinear Fitting using SRIMP Program



## Electropolished

- $mfp = 522 \pm 29$  nm
- $gap = 2.17 \pm .03$



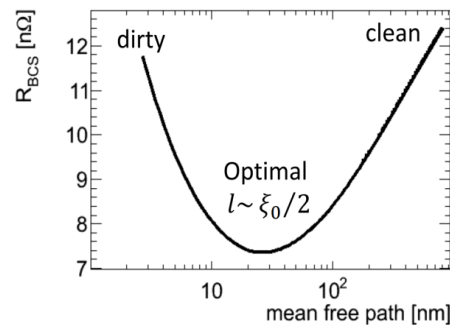
## Low Temperature Bake

- $mfp = 64.7 \pm 6.9$  nm → decrease suggests decreased BCS resistance
- $gap = 2.32 \pm .04$  → increase suggests doped behavior

## Summary

- Low RRR cavity in EP condition behaves differently than high RRR EP
  - Intrinsic impurities do have significant impact on RF behavior
- Low RRR cavity in LTB condition behaves similarly to high RRR LTB with some offset
  - Addition of oxygen into RF layer allows for higher quality factor and accelerating gradients without increasing the residual resistance from EP
  - How does oxygen behave differently in a Nb lattice with more impurities?
- Low RRR shows:
  - consistently high residual resistance
  - low BCS resistance, especially at mid gradient
  - dip on frequency versus temperature near  $T_c$
  - decrease in mfp and increase in gap from EP  $\rightarrow$  LTB

Recall:





## Next Steps

- Processing additional data from LTB testing
  - Temperature-mapping to observe local heating and quench
- N-doping cavity
- Sample study on low RRR material
  - Process coupons to establish EP, LTB, and N-doped conditions
  - Secondary-ion mass spectrometry to observe impurity profile
  - Microscopy to characterize surface



# Questions?

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